

IDS 04/27/2006

INFORMATION DISCLOSURE CITATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) DE920020016US1		Application Number 10/620957			
				Applicant(s) Appinger et al				RECEIVED APR 27 2006 CENTRAL FAX CENTER	
				Filing Date 7/30/2003		Group Art Unit 2138			
U.S. PATENT DOCUMENTS									
*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
U.S. PATENT APPLICATION PUBLICATIONS									
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FOREIGN PATENT DOCUMENTS									
	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation YES NO		
OTHER DOCUMENTS <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>									
PC		"LFSR-Coded Test Patterns for Scan Designs" by B. Kouemann, Pages 237-242							
PC		"Decompression of Test Data Using Variable-Length Seed LFSRs" by J. Rajski et al, 1995 IEEE, Pages 426-433							
EXAMINER /Phung Chung/				DATE CONSIDERED 06/09/2006					
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